

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:
Chen, et al.

Serial No.: 10/741,824

Confirmation No.: 2621

Filed: December 19, 2003

For: Enhancement of CU Line
Reliability Using Thin ALD
TaN Film to Cap the CU
Line

Group Art Unit: 2823

Examiner: John M. Parker

MAIL STOP RCE
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

REQUEST FOR NON-ENTRY OF AMENDMENT

Applicants respectfully request non-entry of the Response filed on November 28, 2006, to the Final Office Action dated October 3, 2006. Applicants also respectfully request non-entry of the Response filed on December 21, 2006, to the Final Office Action dated October 3, 2006.

Respectfully submitted,

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